

X-flash detector – specification

30 mm² XFlash detector with 12.5 microns Be window
(incl. UHV CF flange and bellow)

Peltier cooling (LN2-free)

Energy resolution < 130 eV at Mn K-alpha

Signal processor unit SVE III

Signal processor connector for time-resolved x-ray spectroscopy

I/O Megalink interface

Parallel port adapter

ESPRIT QM100 spectra acquisition software for Windows 7

Spectrometer control PC

X-ray measurement system which should fulfil following requirements:

System for time and energy resolved X-ray spectroscopy for the measurement of X-rays emitted by a Dresden EBIT. The X-rays are measured in dependence on the electron energy or the ionization time. The measured data can be plotted and saved for further investigations. The ion trap time of the EBIT is controlled by the system in the time resolved operation mode. Measured X-rays are detected in dependence on the X-ray energy and the ionization time and stored in the system. The events are transferred to the measurement computer, stored in a X-ray-energy-time-matrix and displayed in a scatter plot.

Packaging, transport, insurance

Operation manual

Installation of the x-ray measurement system together with the detector at the EBIT in the institute of the buyer.